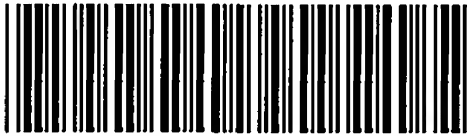


**Search Notes**



**Application/Control No.**

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**Examiner**

Annan Q. Shang

**Applicant(s)/Patent under  
Reexamination**

KLEVEN ET AL.

**Art Unit**

2623

**SEARCHED**

Class	Subclass	Date	Examiner
725	34-36	12/27/2006	A.S

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR